

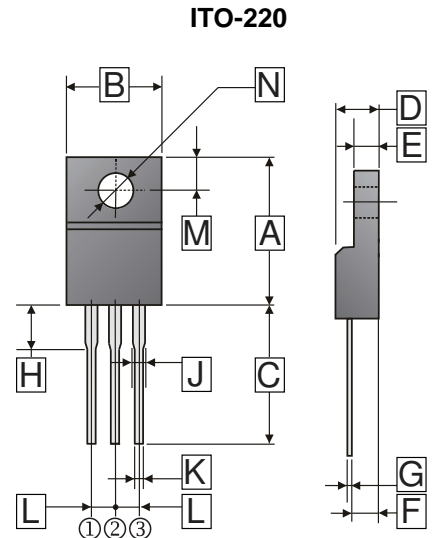
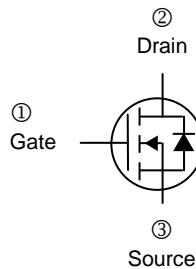
RoHS Compliant Product  
A suffix of "-C" specifies halogen and lead-free

## DESCRIPTION

The N-Channel MOSFET is used an advanced termination scheme to provide enhanced voltage-blocking capability without degrading performance over time. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance. This device is well suited for high efficiency switched mode power suppliers, active power factor correction, electronic lamp ballasts based half bridge topology.

## FEATURES

- Robust high voltage termination
- Avalanche energy specified
- Diode is characterized for use in bridge circuits
- Source to Drain diode recovery time comparable to a discrete fast recovery diode.



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	14.60	15.70	H	2.70	3.80
B	9.50	10.50	J	0.90	1.50
C	12.60	14.00	K	0.50	0.90
D	4.30	4.70	L	2.34	2.74
E	2.30	3.2	M	2.40	3.00
F	2.30	2.80	N	$\phi 3.0$	$\phi 3.4$
G	0.30	0.70			

## ABSOLUTE MAXIMUM RATINGS ( $T_C=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DS}$	600	V
Gate-Source Voltage	$V_{GS}$	$\pm 30$	V
Continuous Drain Current	$I_D$	4.0	A
Pulsed Drain Current	$I_{DM}$	16	A
Power Dissipation <sup>2</sup>	$P_D$	33	W
Derating factor above 25°C		0.26	W / °C
Single Pulsed Avalanche Energy <sup>1</sup>	$E_{AS}$	330	mJ
Repetitive Avalanche Energy <sup>2</sup>	$E_{AR}$	7.3	mJ
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	150,-55~150	°C
<b>Thermal Resistance Rating</b>			
Maximum Junction to Ambient	$R_{\theta JA}$	62.5	°C / W
Maximum Junction to Case	$R_{\theta JC}$	3.79	

Notes:

1.  $L=30\text{mH}$ ,  $I_{AS}=4.4\text{A}$ ,  $V_{DD}=85\text{V}$ ,  $R_G=25\Omega$ , Starting  $T_J=25^\circ\text{C}$
2. Repetitive Rating: Pulse width limited by maximum junction temperature

**ELECTRICAL CHARACTERISTICS** ( $T_A=25^\circ\text{C}$  unless otherwise specified)

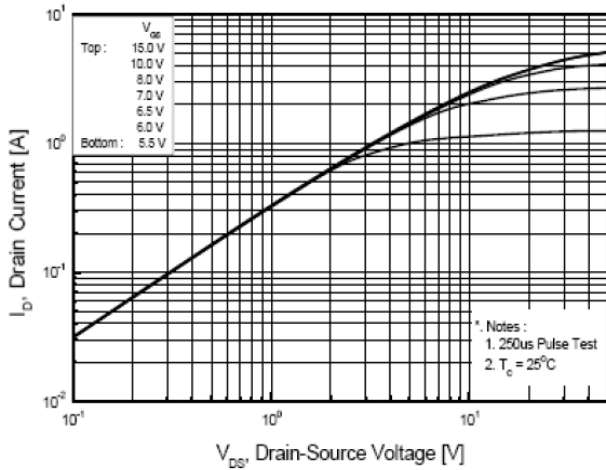
Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
<b>Static</b>						
Gate-Threshold Voltage	$V_{GS(th)}$	2.0	-	4.0	V	$V_{DS}=V_{GS}$ , $I_D=250\mu\text{A}$
Drain-Source On-Resistance	$R_{DS(ON)}$	-	2.0	2.4	$\Omega$	$V_{GS}=10\text{V}$ , $I_D=2\text{A}$
Drain-Source Breakdown Voltage	$BV_{DSS}$	600	-	-	V	$V_{GS}=0$ , $I_D=250\mu\text{A}$
Zero Gate Voltage Drain Current	$I_{DSS}$	-	-	10	$\mu\text{A}$	$V_{DS}=600\text{V}$ , $V_{GS}=0$
Gate-Body Leakage Current, Forward	$I_{GSSF}$	-	-	100	nA	$V_{GS}=30\text{V}$ , $V_{DS}=0$
Gate-Body Leakage Current, Reverse	$I_{GSSR}$	-	-	-100	nA	$V_{GS}=-30\text{V}$ , $V_{DS}=0$
<b>Dynamic</b>						
Total Gate Charge <sup>1,2</sup>	$Q_g$	-	19.8	-	nC	$V_{DS}=480\text{V}$ , $I_D=4.4\text{A}$ , $V_{GS}=10\text{V}$
Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$	-	4	-		
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$	-	7.2	-		
Turn-on Delay Time <sup>1,2</sup>	$T_{d(on)}$	-	27	-	nS	$V_{DD}=300\text{V}$ , $I_D=4.4\text{A}$ , $R_G=25\Omega$
Rise Time <sup>1,2</sup>	$T_r$	-	19	-		
Turn-off Delay Time <sup>1,2</sup>	$T_{d(off)}$	-	160	-		
Fall Time <sup>1,2</sup>	$T_f$	-	22	-	pF	$V_{DS}=25\text{V}$ , $V_{GS}=0$ , $f=1.0\text{MHz}$
Input Capacitance	$C_{iss}$	-	672	-		
Output Capacitance	$C_{oss}$	-	66	-		
Reverse Transfer Capacitance	$C_{rss}$	-	4.7	-		
Maximum Continuous Drain-Source Diode Forward Current	$I_S$	-	-	4.0	A	
Maximum Pulsed Drain-Source Diode Forward Current	$I_{SM}$	-	-	16	A	
Drain-Source Diode Forward Voltage	$V_{SD}$	-	-	1.4	V	$V_{GS}=0$ , $I_S=4.0\text{A}$
Reverse Recovery Time	$T_{rr}$	-	300	-	nS	$V_{GS}=0$ , $I_S=4.0\text{A}$ ,
Reverse Recovery Charge <sup>1</sup>	$Q_{rr}$	-	2.2	-	$\mu\text{C}$	$I_F / dt = 100\text{A}/\mu\text{s}$

Notes:

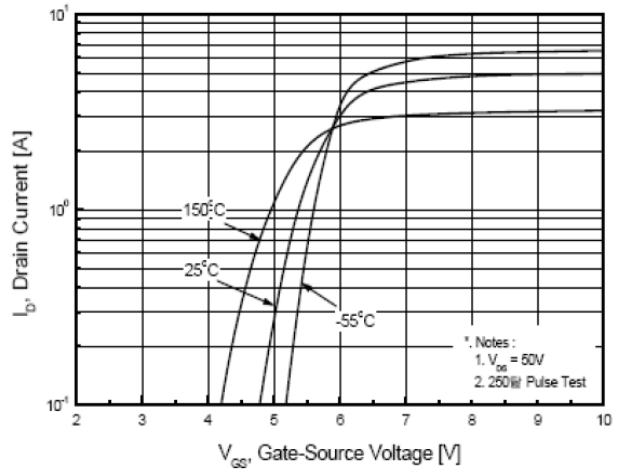
1. Pulse Test: Pulse width < 300us, Duty cycle  $\leq$  2%.
2. Basically not affected by working temperature.

**CHARACTERISTIC CURVE**

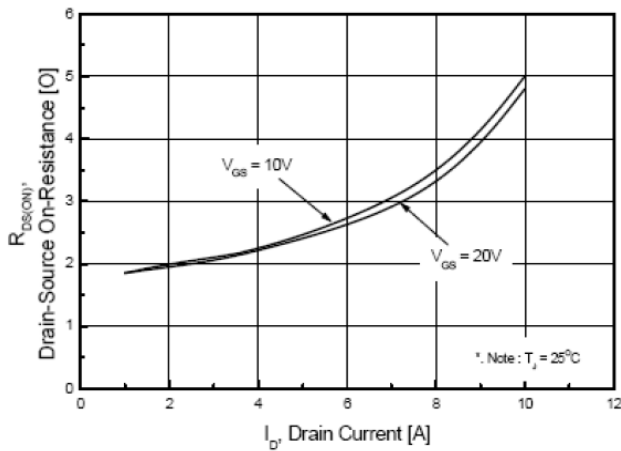
**Fig 1. On-State Characteristics**



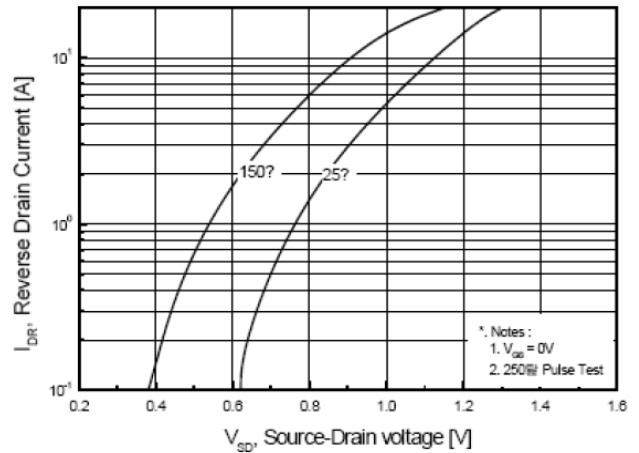
**Fig 2. Transfer Characteristics**



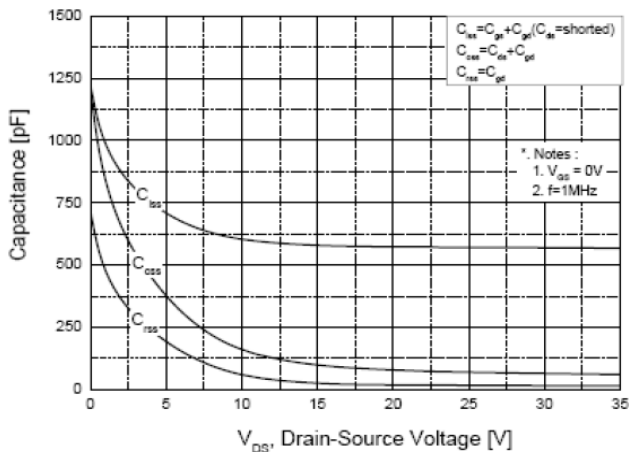
**Fig 3. On Resistance Variation vs. Drain Current and Gate Voltage**



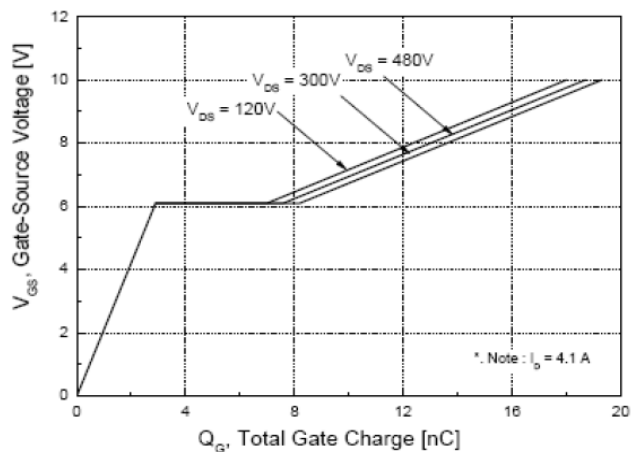
**Fig 4. On State Current vs. Allowable Case Temperature**



**Fig 5. Capacitance Characteristics ( Non-Repetitive )**

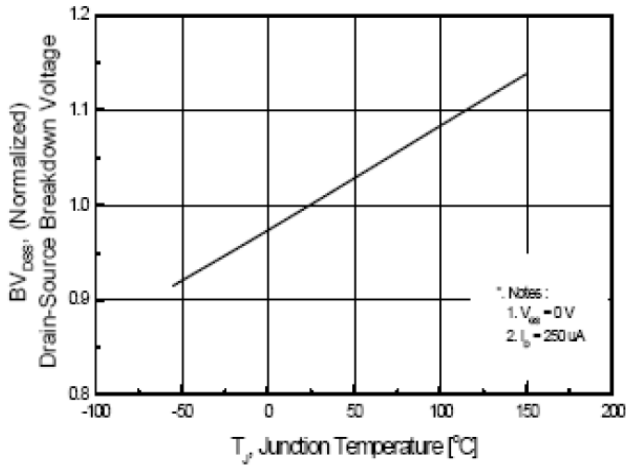


**Fig 6. Gate Charge Characteristics**

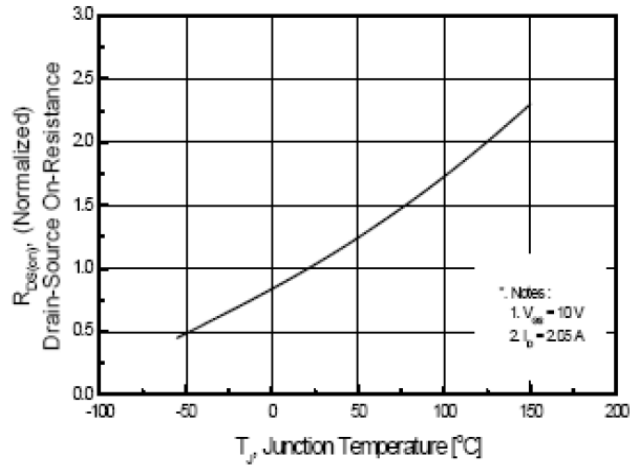


**CHARACTERISTIC CURVE**

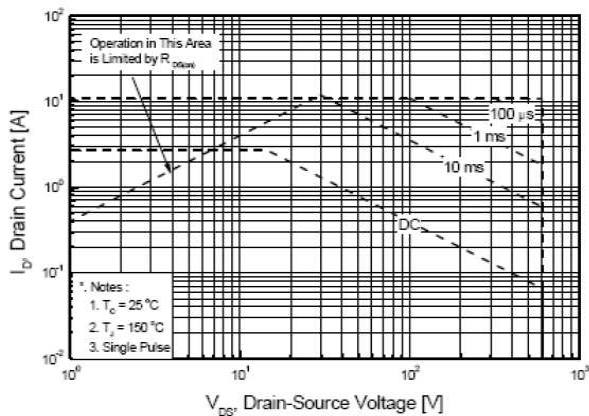
**Fig 7. Breakdown Voltage Variation vs. Junction Temperature**



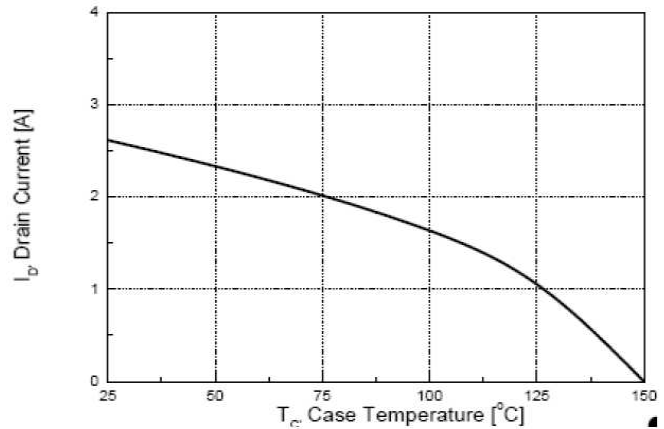
**Fig 8. On-Resistance Variation vs. Junction Temperature**



**Fig 9. Maximum Safe Operating Area (TO-220F)**



**Fig 10. Maximum Drain Current vs. Case Temperature. (TO220F)**



**Fig 11. Transient Thermal Response Curve(TO220F)**

